Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/781,554	CHATTERJEE I	ET AL.
Examiner	Art Unit	
Melvin Marcelo	2662	

	SEARCHED				
Class	Subclass	Date	Examiner		
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709	203	4-2005	mm		
	219				
711	118)			
		 			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
370	429	7		
709	203,219	74-2005	mm	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	. EXMR	
East	4-2009	ann	
Inventor Name searched PARM —	- Y-200 S	ma	